Notice of References Cited

Application/Control No. 10/785,084	Reexaminati	Applicant(s)/Patent Under Reexamination TANAKA ET AL.		
Examiner	Art Unit			
David Sample	1755	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	А	US-2002/0182141	12-2002	Uchida, Yoshio	423/608
*	В	US-5,928,977	07-1999	Magnin et al.	501/87
*	С	US-5,336,282	08-1994	Ghosh et al.	51/309
*	D	US-5,292,693	03-1994	Kaga et al.	501/103
*	E	US-4,774,041	09-1988	Tsukuma et al.	264/664
*	F	US-4,370,393	01-1983	Watanabe et al.	429/304
*	G	US-4,360,598	11-1982	Otagiri et al.	501/103
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08119730 A	05-1996	Japan	HIRAMATSU, NOBUKI	C04B 35/48
	0	JP 06009220 A	01-1994	Japan	YAMAMOTO et al.	C01G 25/00
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

		The state of the s
*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.